Search Notes



Applicat	ion/Contro	l No.

Applicant(s)/Patent under Reexamination

TAKAHASHI ET AL.

10/035,434

Examiner

Art Unit

Robert DeBeradinis

2836

	SEARCHED				
Class	Subclass	Date	Examiner		
307	140	1/13/2005	RLD		
327	65	1/13/2005	RLD		
307	139	1/13/2005	RLD		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
307	140	1/13/05	RA	
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